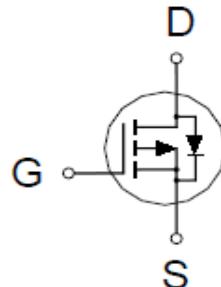


PE537BA

P-Channel Logic Level Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-30V	8.5mΩ @ $V_{GS} = -10V$	-33A



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ³	I_D	-33	A
		-22	
		-12	
		-9.6	
Pulsed Drain Current ¹	I_{DM}	-100	
Avalanche Current	I_{AS}	-34	
Avalanche Energy	E_{AS}	57.8	mJ
Power Dissipation	P_D	16.7	W
		6.7	
		2	
		1.3	
Junction & Storage Temperature Range	T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		60	°C / W
Junction-to-Case	$R_{\theta JC}$		7.5	

¹Pulse width limited by maximum junction temperature.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ C$.

³Package limitation current is 22A.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

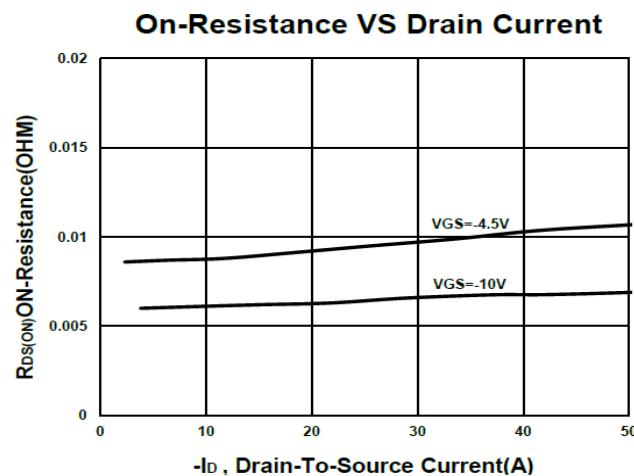
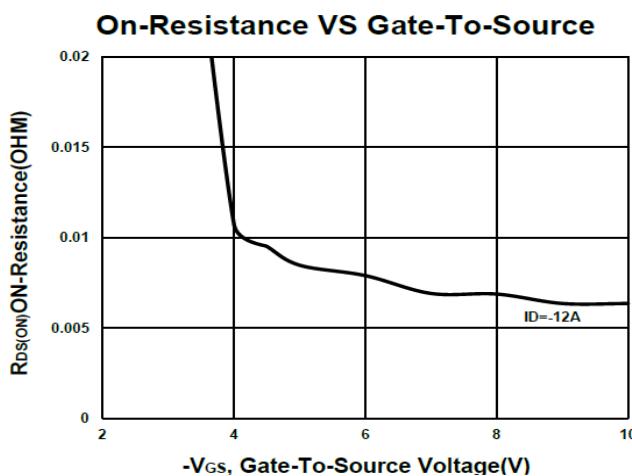
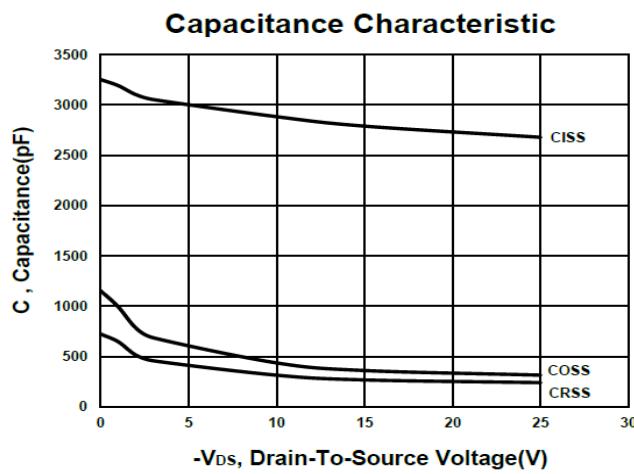
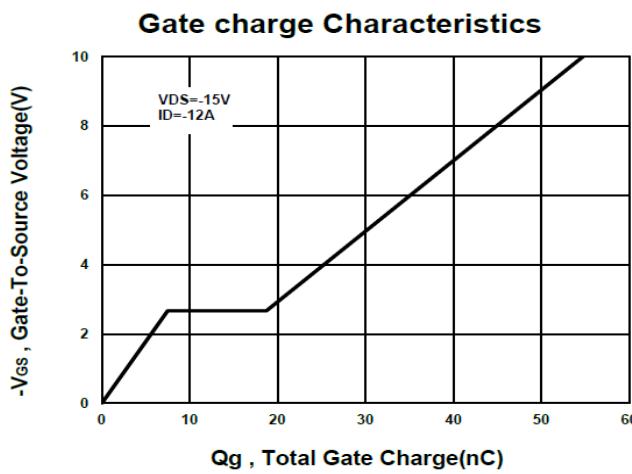
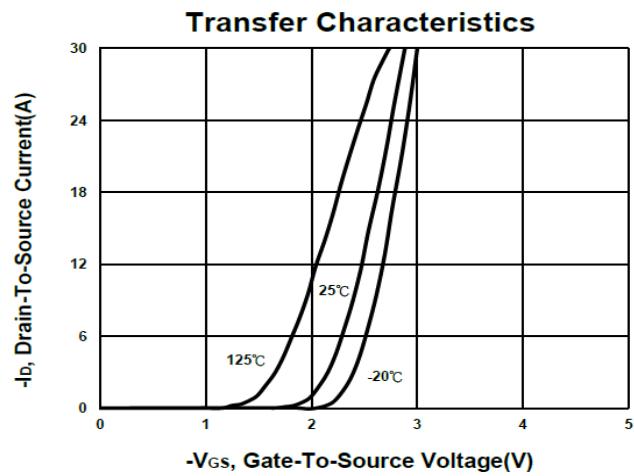
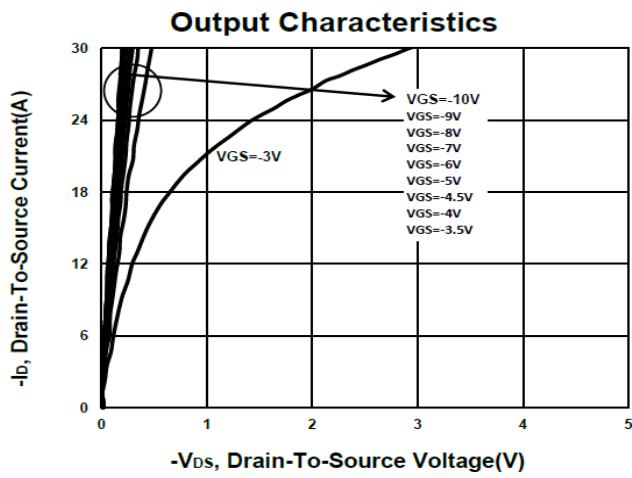
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-1	-1.6	-3	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -24\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
		$V_{\text{DS}} = -20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			-10	
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -12\text{A}$		9.9	14	$\text{m}\Omega$
		$V_{\text{GS}} = -10\text{V}, I_D = -12\text{A}$		6.9	8.5	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = -10\text{V}, I_D = -12\text{A}$		35		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -15\text{V}, f = 1\text{MHz}$		2803		pF
Output Capacitance	C_{oss}			371		
Reverse Transfer Capacitance	C_{rss}			286		
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		4		Ω
Total Gate Charge ²	$Q_g(V_{\text{GS}} = -10\text{V})$	$V_{\text{DS}} = -15\text{V}, I_D = -12\text{A}$		56		nC
	$Q_g(V_{\text{GS}} = -4.5\text{V})$			28		
Gate-Source Charge ²	Q_{gs}			8		
Gate-Drain Charge ²	Q_{gd}			12		
Turn-On Delay Time ²	$t_{\text{d(on)}}$	$V_{\text{DD}} = -10\text{V}, I_D \approx -12\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GEN}} = 6\Omega$		21		nS
Rise Time ²	t_r			25		
Turn-Off Delay Time ²	$t_{\text{d(off)}}$			100		
Fall Time ²	t_f			73		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				-12.8	A
Forward Voltage ¹	V_{SD}	$I_F = -12\text{A}, V_{\text{GS}} = 0\text{V}$			-1.3	V
Reverse Recovery Time	t_{rr}	$I_F = -12\text{A}, dI/dt = 100\text{A} / \mu\text{s}$		26		nS
Reverse Recovery Charge	Q_{rr}			14		nC

¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

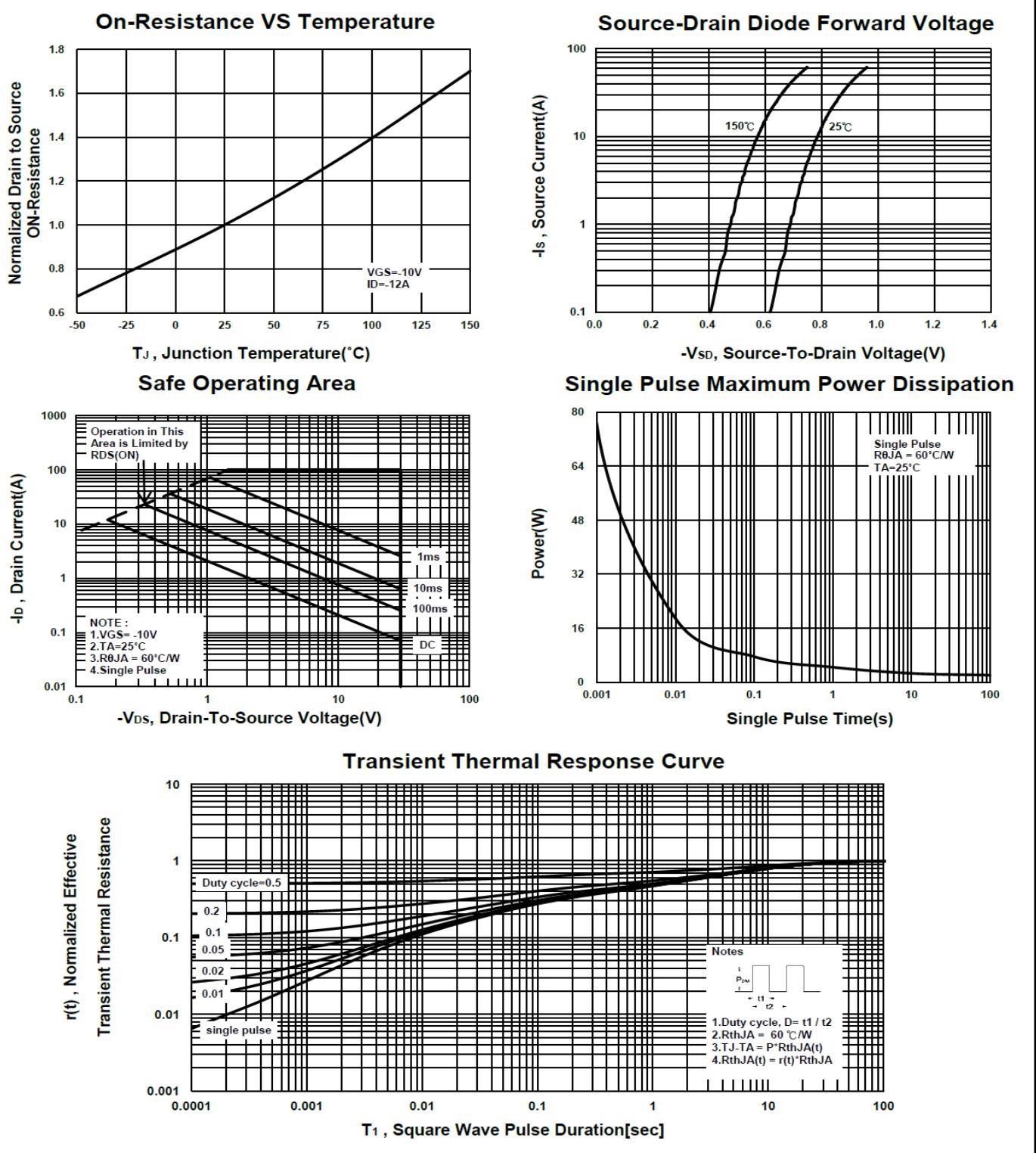
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Package Dimension

PDFN 3x3P MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	3		3.6	I	0.7		1.12
B	2.88		3.2	J	0.1		0.33
C	2.9		3.2	K	0.6		
D	1.98		2.69	L	0°	10°	12°
E	3		3.6	M	0.14		0.41
F	0		0.455	N	0.6		0.7
G	1.47		2.2	O	0.12		0.36
H	0.15		0.56	P	0		0.2

